

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOSIII)

TPCS8204

Lithium Ion Battery Applications
Notebook PC Applications
Portable Equipment Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance: $R_{DS(ON)} = 13 \text{ m}\Omega$ (typ.)
- High forward transfer admittance: $|Y_{fs}| = 15 \text{ S}$ (typ.)
- Low leakage current: $I_{DSS} = 10 \text{ }\mu\text{A}$ (max) ($V_{DS} = 20 \text{ V}$)
- Enhancement-mode: $V_{th} = 0.5 \sim 1.2 \text{ V}$ ($V_{DS} = 10 \text{ V}$, $I_D = 200 \text{ }\mu\text{A}$)

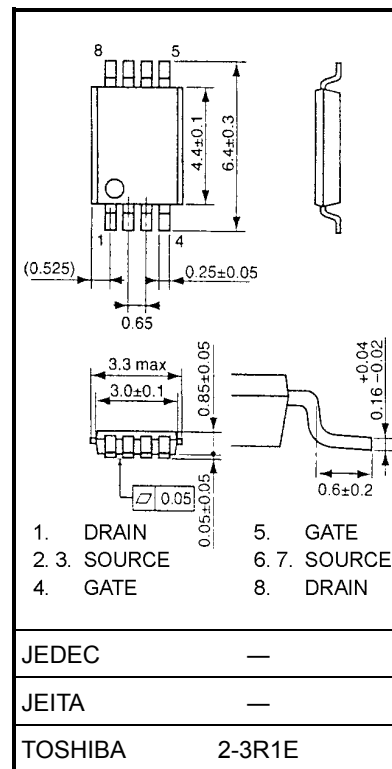
Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Rating	Unit
Drain-source voltage	V_{DSS}	20	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	V_{DGR}	20	V
Gate-source voltage	V_{GSS}	± 12	V
Drain current	DC (Note 1)	I_D	A
	Pulse (Note 1)	I_{DP}	
Drain power dissipation ($t = 10 \text{ s}$) (Note 2a)	Single-device operation (Note 3a)	$P_D (1)$	W
	Single-device value at dual operation (Note 3b)	$P_D (2)$	
Drain power dissipation ($t = 10 \text{ s}$) (Note 2b)	Single-device operation (Note 3a)	$P_D (1)$	W
	Single-device value at dual operation (Note 3b)	$P_D (2)$	
Single pulse avalanche energy (Note 4)	E_{AS}	46.8	mJ
Avalanche current	I_{AR}	6	A
Repetitive avalanche energy Single-device value at dual operation (Note 2a, 3b, 5)	E_{AR}	0.075	mJ
Channel temperature	T_{ch}	150	$^\circ\text{C}$
Storage temperature range	T_{stg}	$-55 \sim 150$	$^\circ\text{C}$

Note: For (Note 1), (Note 2), (Note 3), (Note 4) and (Note 5), please refer to the next page.

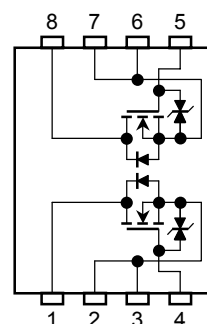
This transistor is an electrostatic sensitive device. Please handle with caution.

Unit: mm



Weight: 0.035 g (typ.)

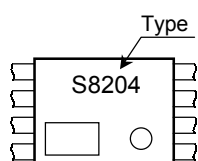
Circuit Configuration



Thermal Characteristics

Characteristics		Symbol	Max	Unit
Thermal resistance, channel to ambient ($t = 10$ s)	Single-device operation (Note 3a)	$R_{th(ch-a)}(1)$	114	$^{\circ}\text{C/W}$
	Single-device value at dual operation (Note 3b)	$R_{th(ch-a)}(2)$	167	
Thermal resistance, channel to ambient ($t = 10$ s)	Single-device operation (Note 3a)	$R_{th(ch-a)}(1)$	208	$^{\circ}\text{C/W}$
	Single-device value at dual operation (Note 3b)	$R_{th(ch-a)}(2)$	357	

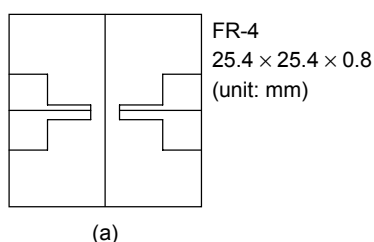
Marking (Note 6)



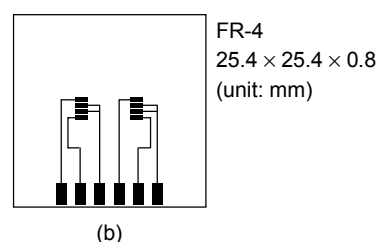
Note 1: Please use devices on condition that the channel temperature is below 150°C .

Note 2:

a) Device mounted on a glass-epoxy board (a)



b) Device mounted on a glass-epoxy board (b)



Note 3:

- The power dissipation and thermal resistance values are shown for a single device. (During single-device operation, power is only applied to one device.)
- The power dissipation and thermal resistance values are shown for a single device. (During dual operation, power is evenly applied to both devices.)

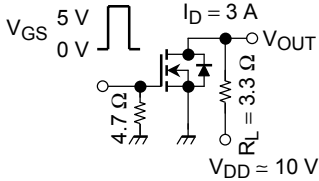
Note 4: $V_{DD} = 16$ V, $T_{ch} = 25^{\circ}\text{C}$ (initial), $L = 1.0$ mH, $R_G = 25$ Ω , $I_{AR} = 6$ A

Note 5: Repetitive rating; pulse width limited by maximum channel temperature

Note 6: • on lower left of the marking indicates Pin 1.

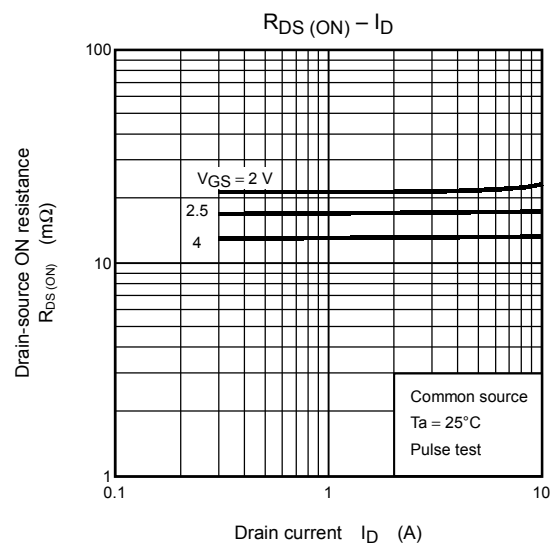
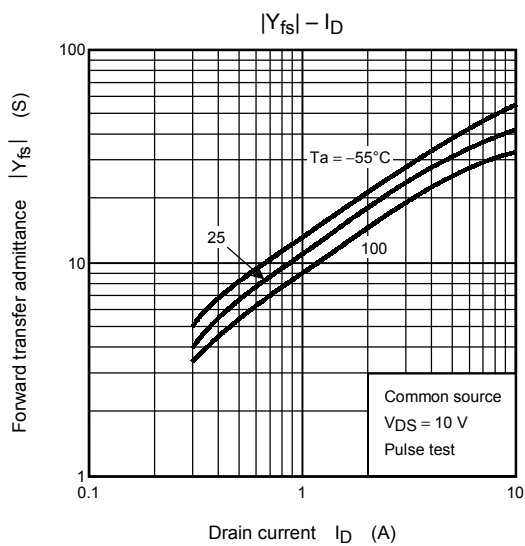
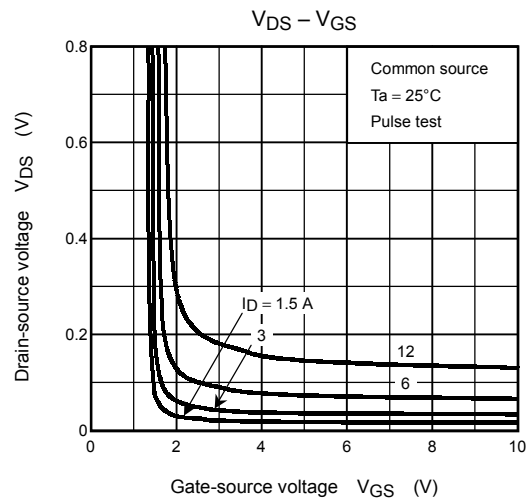
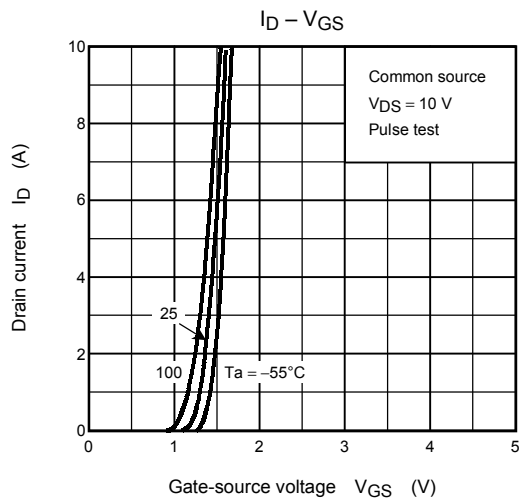
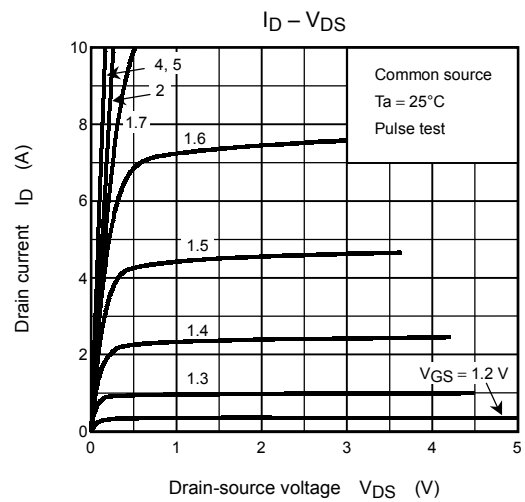
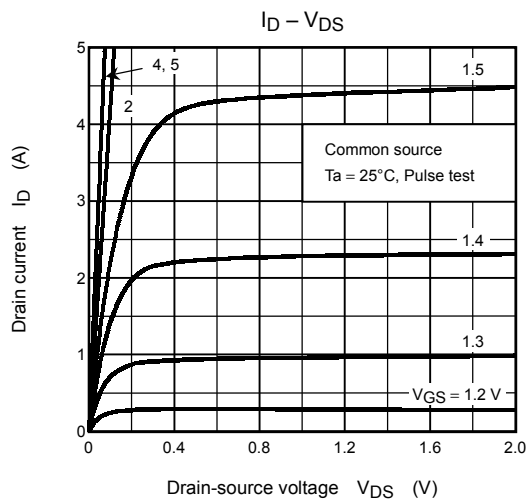
* shows lot number. (year of manufacture: last decimal digit of the year of manufacture, month of manufacture: January to December are denoted by letters A to L respectively.)

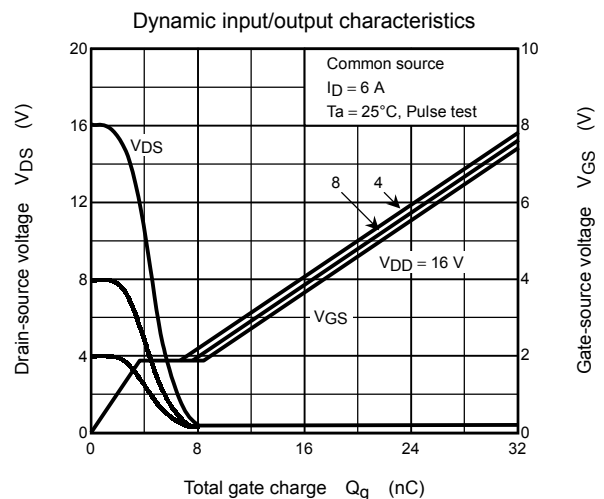
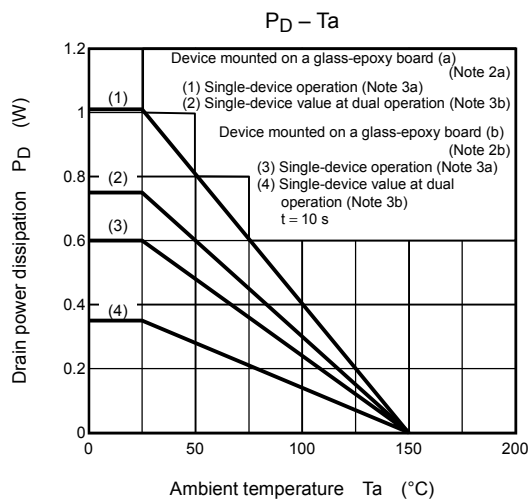
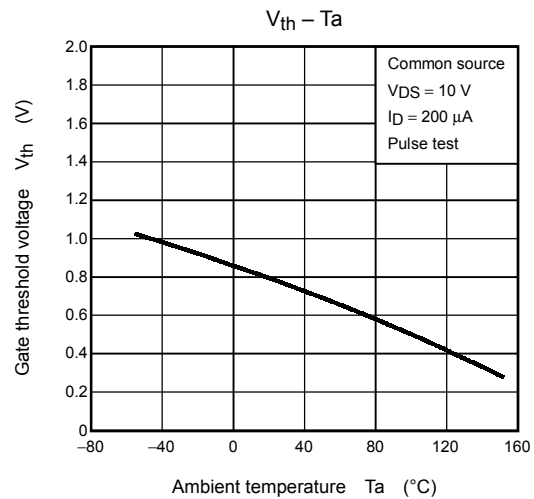
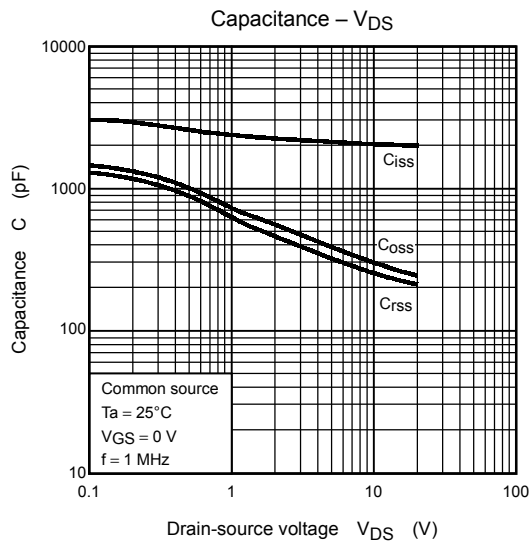
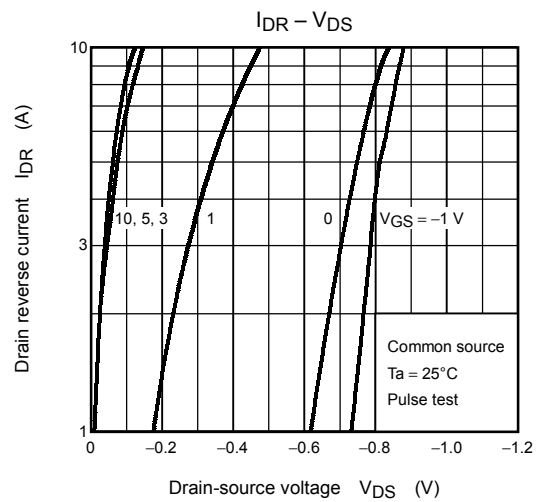
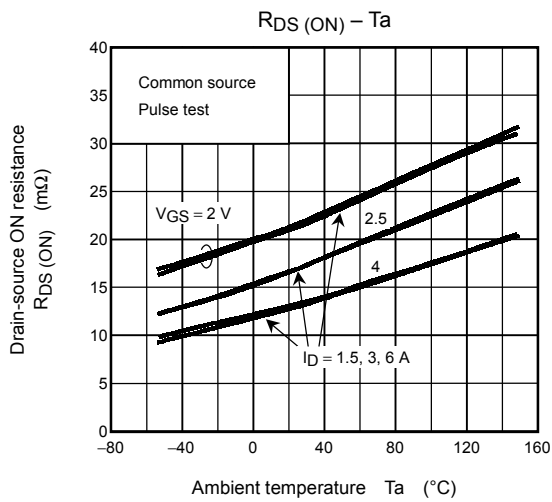
Electrical Characteristics (Ta = 25°C)

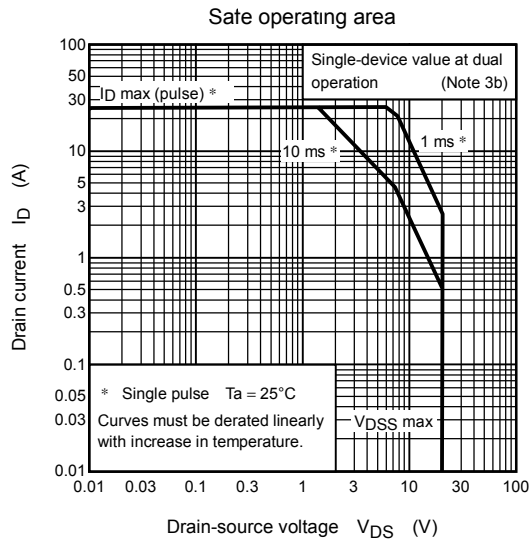
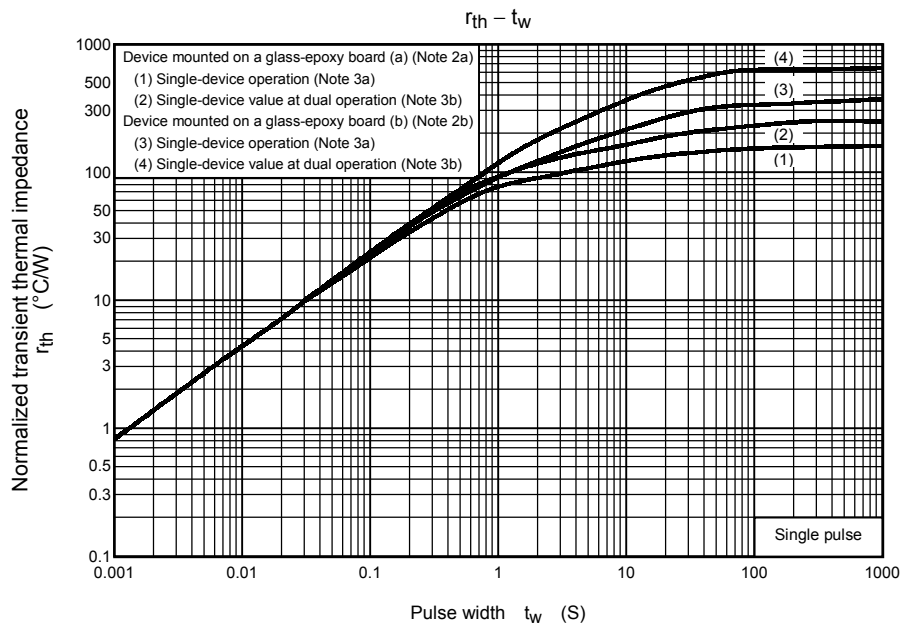
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	—	—	± 10	μA
Drain cut-OFF current		I_{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$	—	—	10	μA
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	20	—	—	V
		$V_{(BR)DSX}$	$I_D = 10 \text{ mA}, V_{GS} = -12 \text{ V}$	8	—	—	
Gate threshold voltage		V_{th}	$V_{DS} = 10 \text{ V}, I_D = 200 \mu\text{A}$	0.5	—	1.2	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = 2.0 \text{ V}, I_D = 4.2 \text{ A}$	—	24	35	m Ω
			$V_{GS} = 2.5 \text{ V}, I_D = 4.2 \text{ A}$	—	18	22	
			$V_{GS} = 4.0 \text{ V}, I_D = 4.8 \text{ A}$	—	13	17	
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = 10 \text{ V}, I_D = 3.0 \text{ A}$	7.5	15	—	S
Input capacitance		C_{iss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	—	2160	—	pF
Reverse transfer capacitance		C_{rss}		—	210	—	
Output capacitance		C_{oss}		—	230	—	
Switching time	Rise time	t_r	 <p>$V_{GS} = 5 \text{ V}$ $V_{GS} = 0 \text{ V}$ $I_D = 3 \text{ A}$ V_{OUT} 4.7Ω 33Ω $R_L = 33 \Omega$ $V_{DD} = 10 \text{ V}$ Duty $\leq 1\%$, $t_w = 10 \mu\text{s}$</p>	—	5	—	ns
	Turn-ON time	t_{on}		—	13	—	
	Fall time	t_f		—	10	—	
	Turn-OFF time	t_{off}		—	53	—	
Total gate charge (gate-source plus gate-drain)		Q_g	$V_{DD} = 16 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 6 \text{ A}$	—	22	—	nC
Gate-source charge 1		Q_{gs1}		—	4	—	
Gate-drain ("miller") charge		Q_{gd}		—	5	—	

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Drain reverse current	Pulse (Note 1)	I_{DRP}	—	—	—	24	A
Forward voltage (diode)		V_{DSF}	$I_{DR} = 6 \text{ A}, V_{GS} = 0 \text{ V}$	—	—	-1.2	V







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